# Application/Control No. O9/482.731 Examiner Hai Vo Applicant(s)/Patent Under Reexamination MURAKAMI ET AL. Page 1 of 1

# Notice of References Cited

### **U.S. PATENT DOCUMENTS** Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY 123/195C US-4,522,165 06-1985 Ogawa, Naoki US-В US-С US-D US-Ε US-F US-G US-Н US-1 US-J US-US-L US-М

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	S					
	Т					

### NON-PATENT DOCUMENTS

NON-FATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ						
	>						
	<b>V</b>						
	χ						

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.